aplanoXX



High NA objectives with protective window, compensating spherical aberration when focusing laser beam inside media

Applications:

- Microprocessing sapphire, fused silica, glass, Si, SiC
- 3D micro- and nanofabrication
- Nanostructuring in optical data storage and recording polarization converters
- Selective Laser Etching
- Waveguide recording
- Dicing
- Microscopy

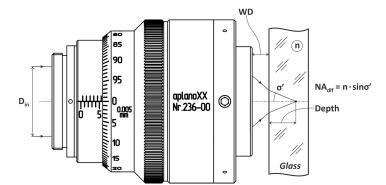
Specifications

		aplanoXX_NA0.8_D20	aplanoXX_NA0.5_D9
Description		Objectives of aplanatic design with • function of compensation of spherical aberration that occurs when focusing laser radiation in transparent media • replaceable protective window	
Accessories		 Window in Holder L9333.06 Protective Window D12_1064, D12_515/1030 Spanner Wrench K-26-0.4x0.4 	
Numerical aperture (NA)		0.8	0.5
Clear Aperture, mm		20	9
Focal length, mm		12.5	8.5
Protective Window		D12, replaceable, installed in Holder L9333.06	
Working Distance, mm	- with window	1.6	4.4
	- without window	2.5	5.5
Range of focusing depth in fused silica*, μm		0 4000	0 1000
Spectral band, nm		_1030: _800: _515:	1020 – 1100 770 - 900 510 – 545
		_800 / 1030:	770 – 900 / 1020 – 1100
Angular field of view *		± 0.3°	± 1°
Recommended maximum pulse energy		100 mJ at 5 ns 300 µJ at 1 ps	25 mJ at 5 ns 100 μJ at 1 ps
Mounting		C-Mount (1"-32 UN 2A), external other threads available on request	
Diameter, mm		44	32
Length with window holder, mm		54	36 42 with Adapter C-Mount Ext/Int 6 n

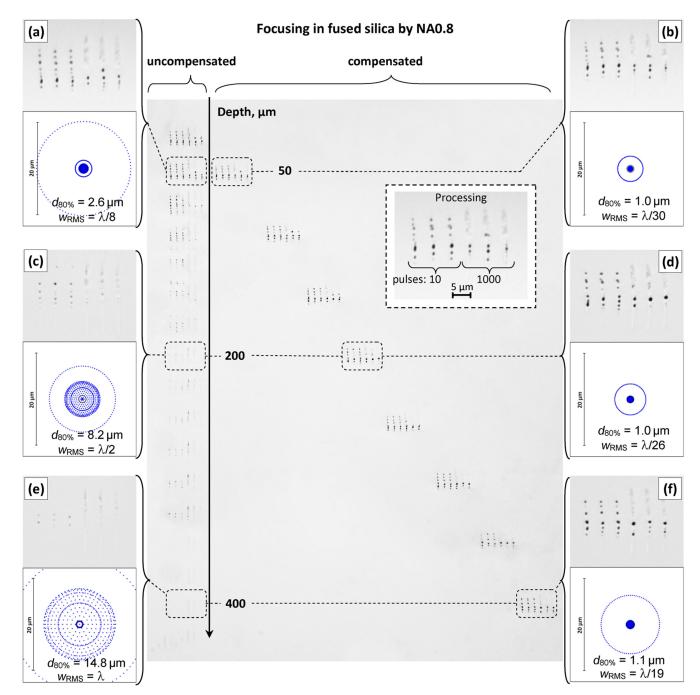
^{* -} by diffraction limited focusing.

In-depth focusing inside transparent media never was so easy!

Specifications are subject to change without notice



Application example focusing fs laser beam inside fused silica



Views of calculated spots and microphotographs of processed areas:
on the left – *no* compensation of spherical aberration, on the right – *with* aberration compensation.

Layout of pulse groups is shown in the image inserted in central microphotograph. (Courtesy of University of Southampton)

